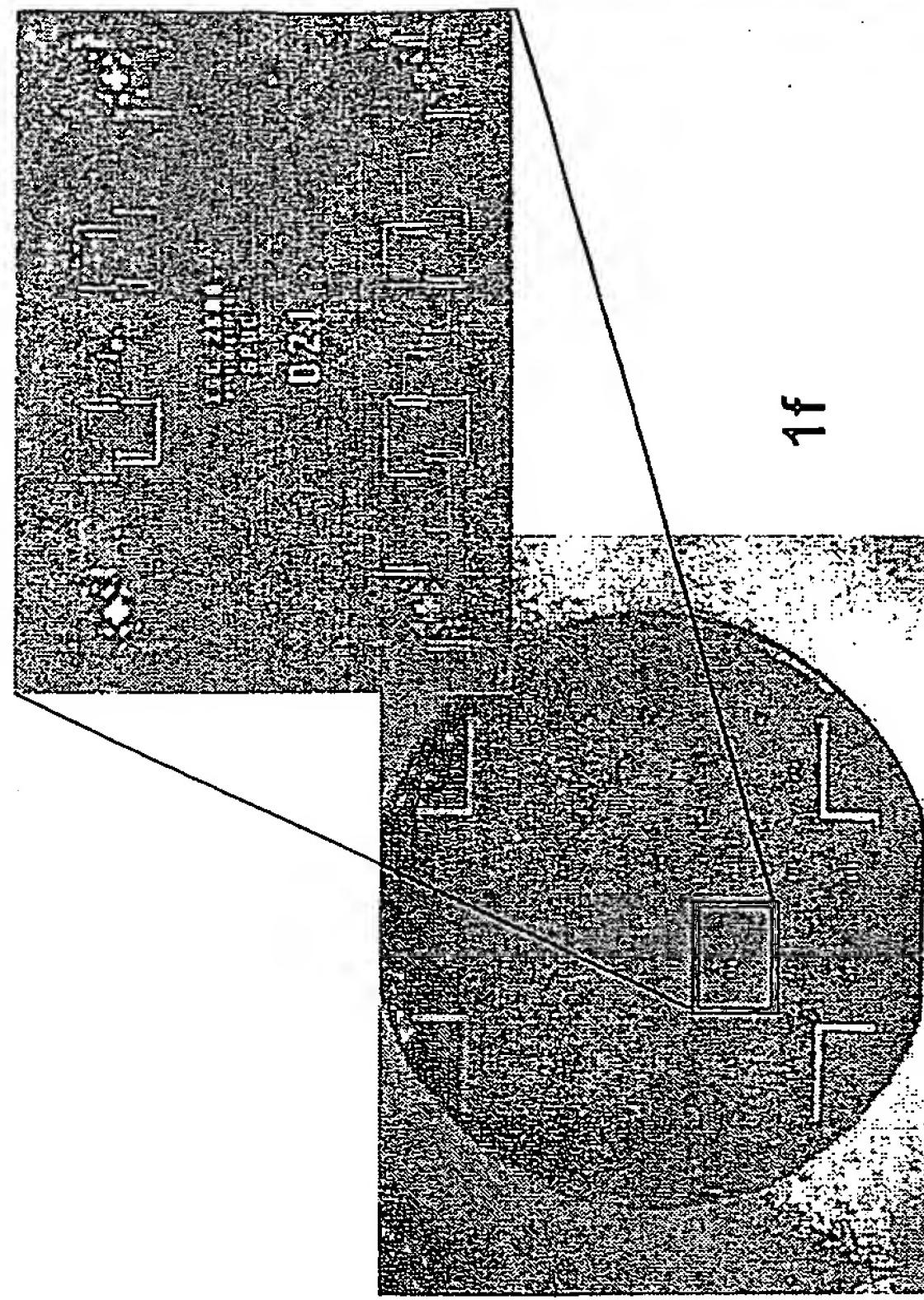
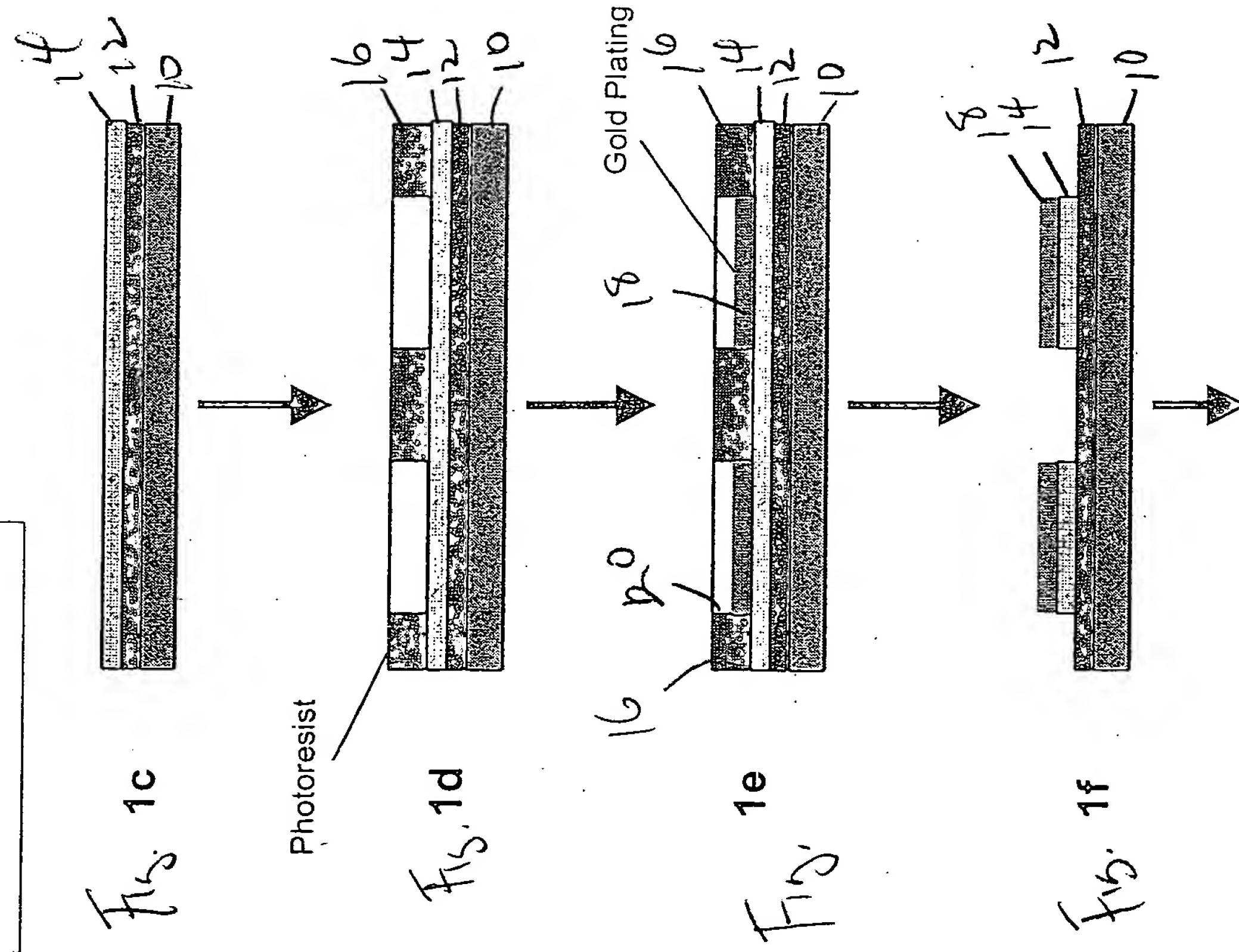


# Reverse Neo Process

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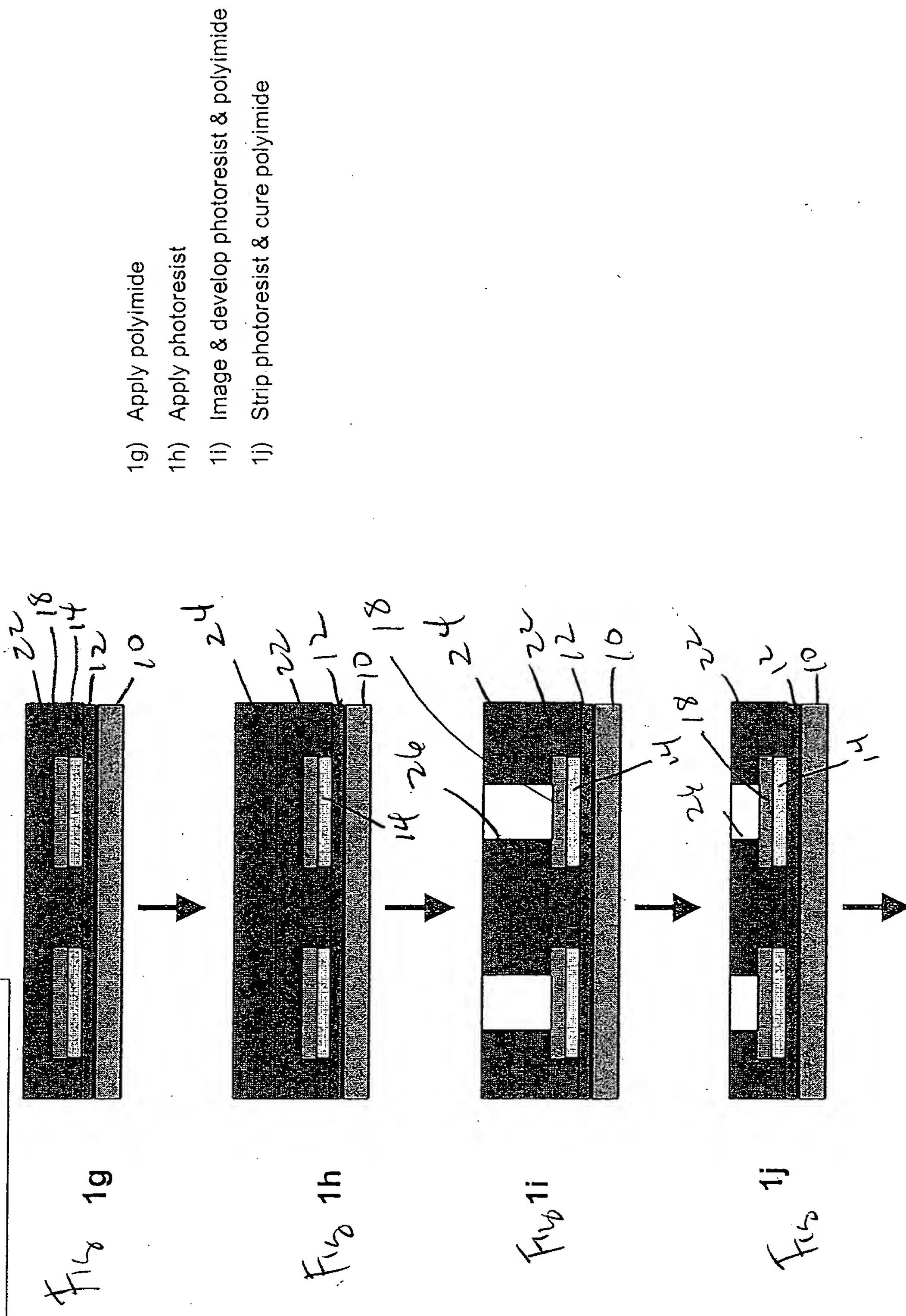


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# Reverse Neo Process

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# Reverse Neo Process

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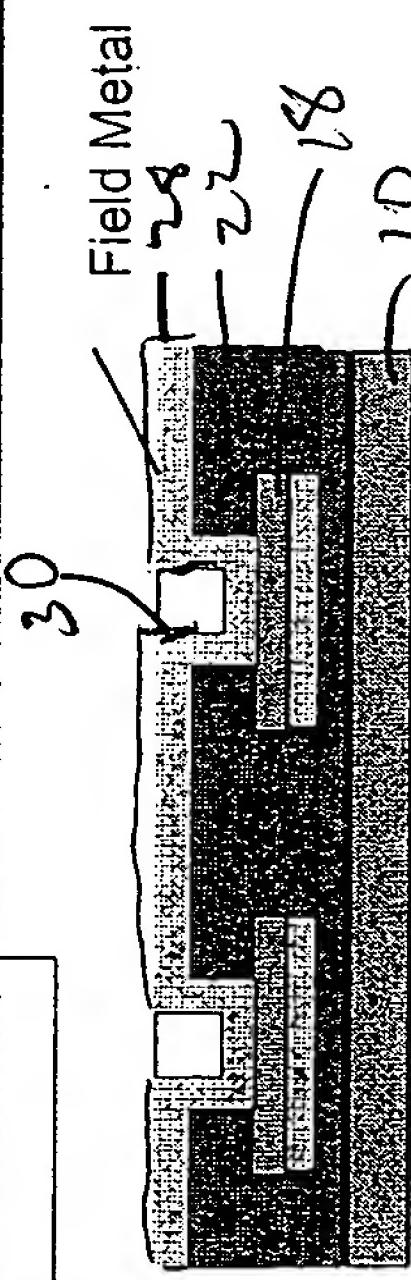


Fig. 1k

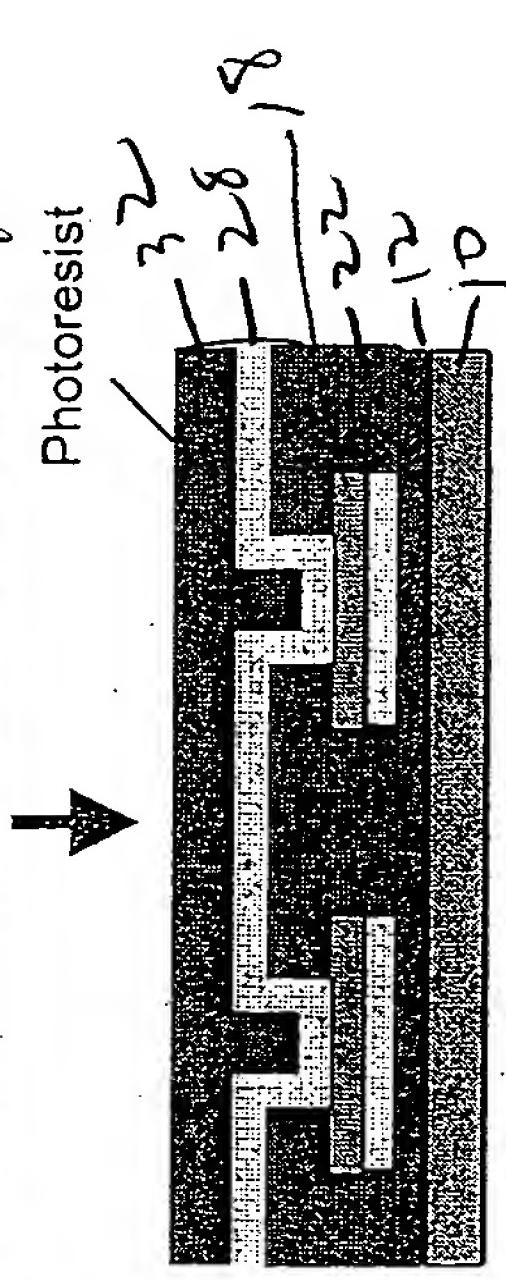


Fig. 1l

- 1k) Apply field metal
- 1l) Apply photoresist
- 1m) Image & develop photoresist. Gold electroplate
- 1n) Strip photoresist & field metal etch

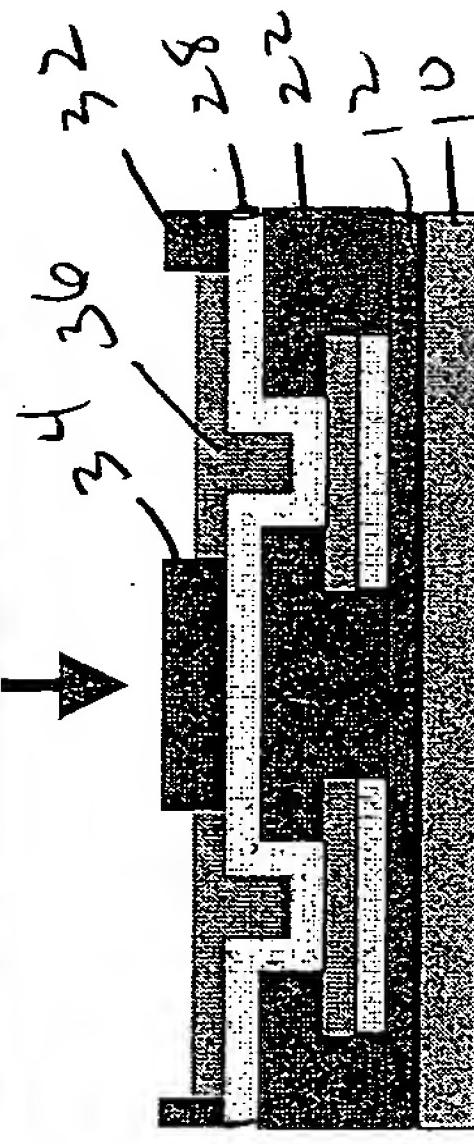


Fig. 1m

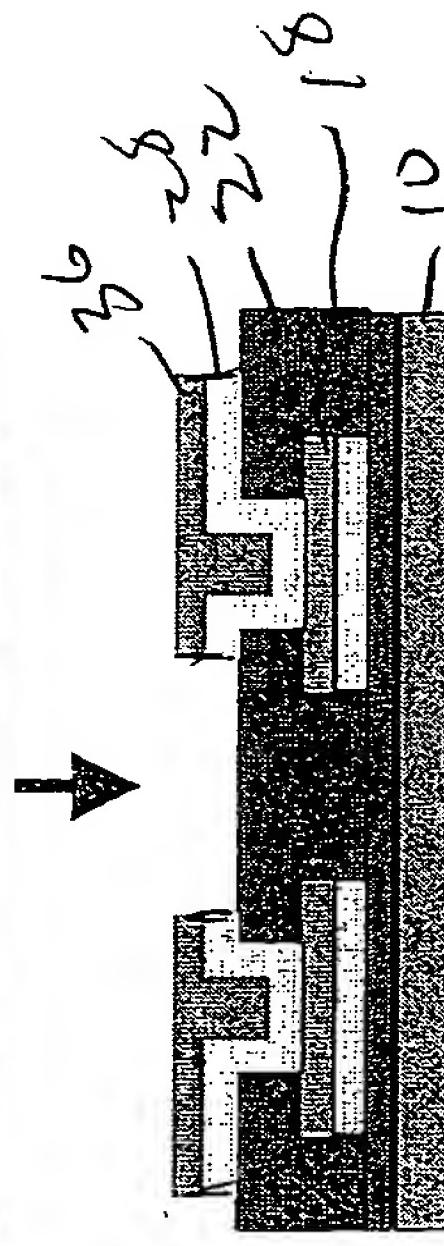


Fig. 1n

NOTE: For additional layers, steps 1g through 1n are repeated.

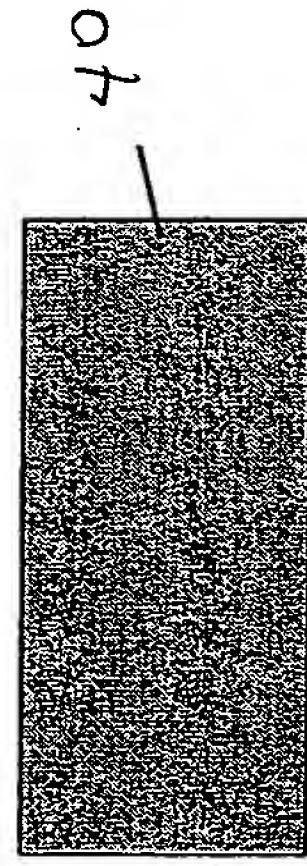
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# Reverse Neo Process

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## Solder Bumping Of Die



- 2a) Retrieve die
- 2b) Apply underbump metallurgy
- 2c) Apply solder bump

Fig. 2a

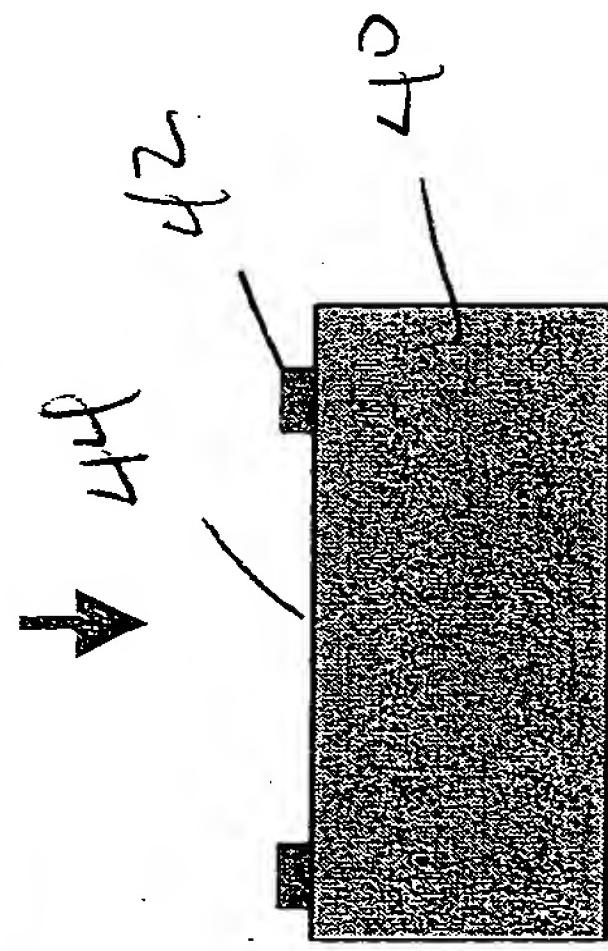


Fig. 2b

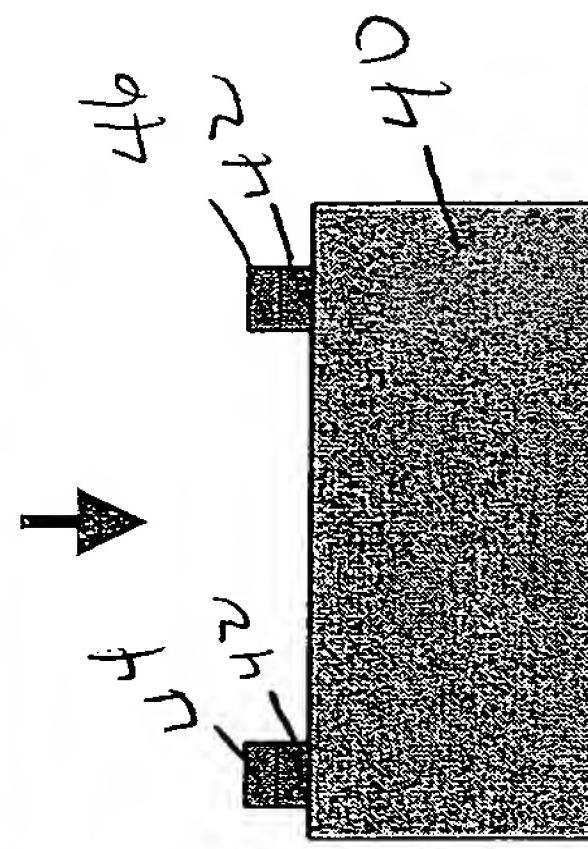
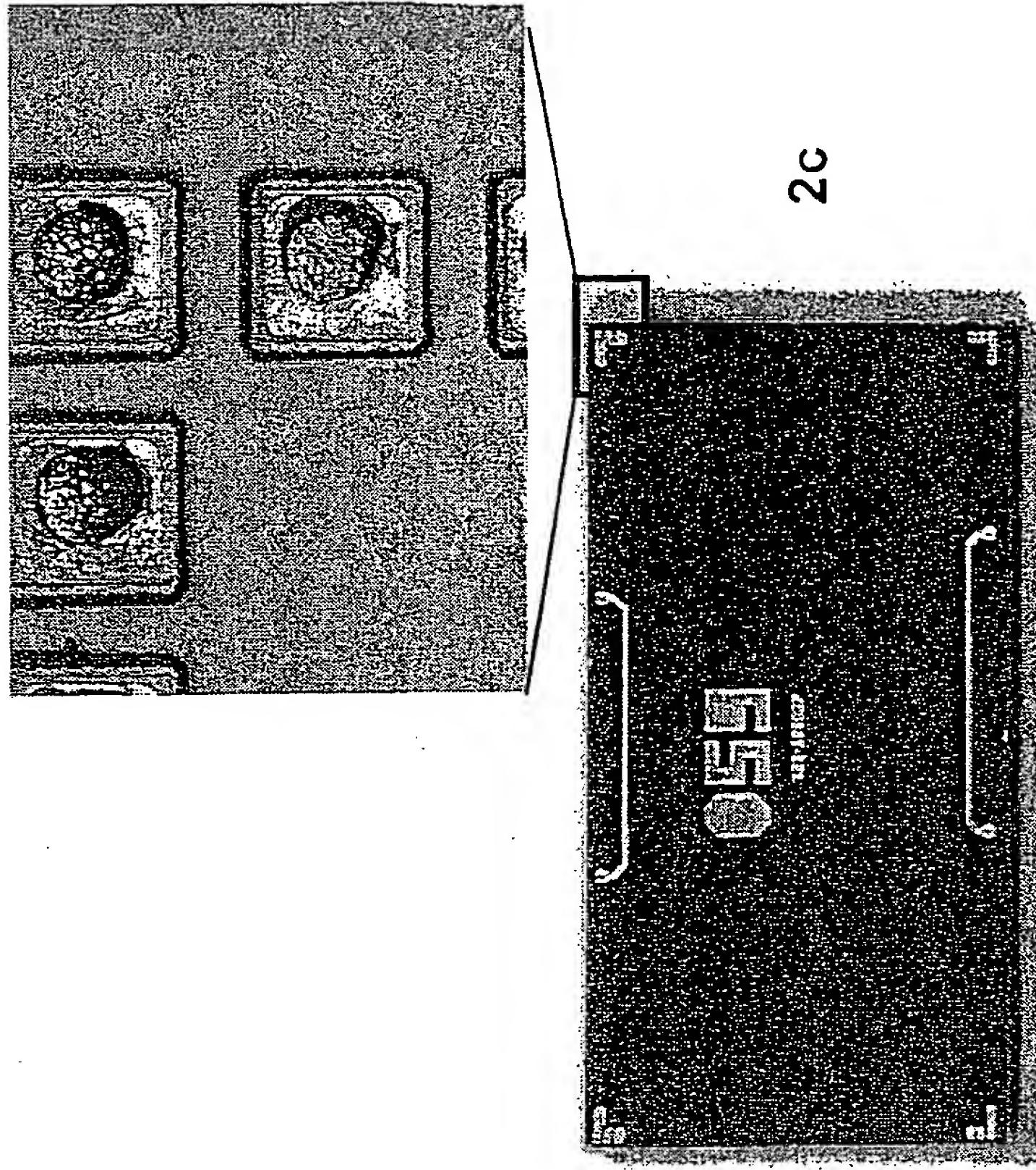


Fig. 2c



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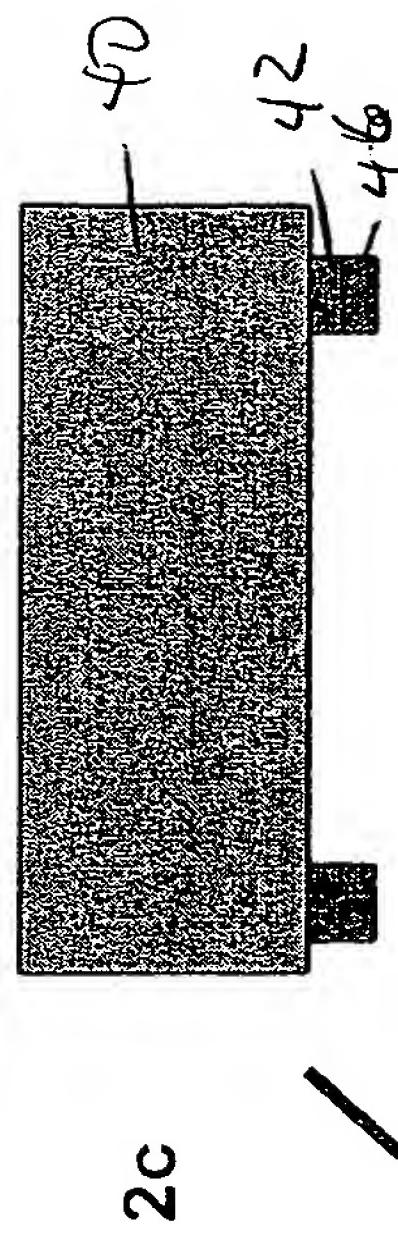
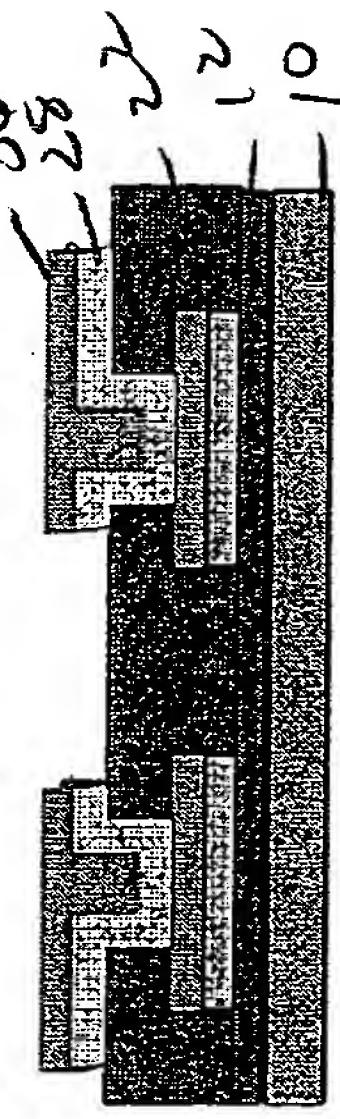
# Reverse Neo Process

IRVINE SENSORS CORPORATION

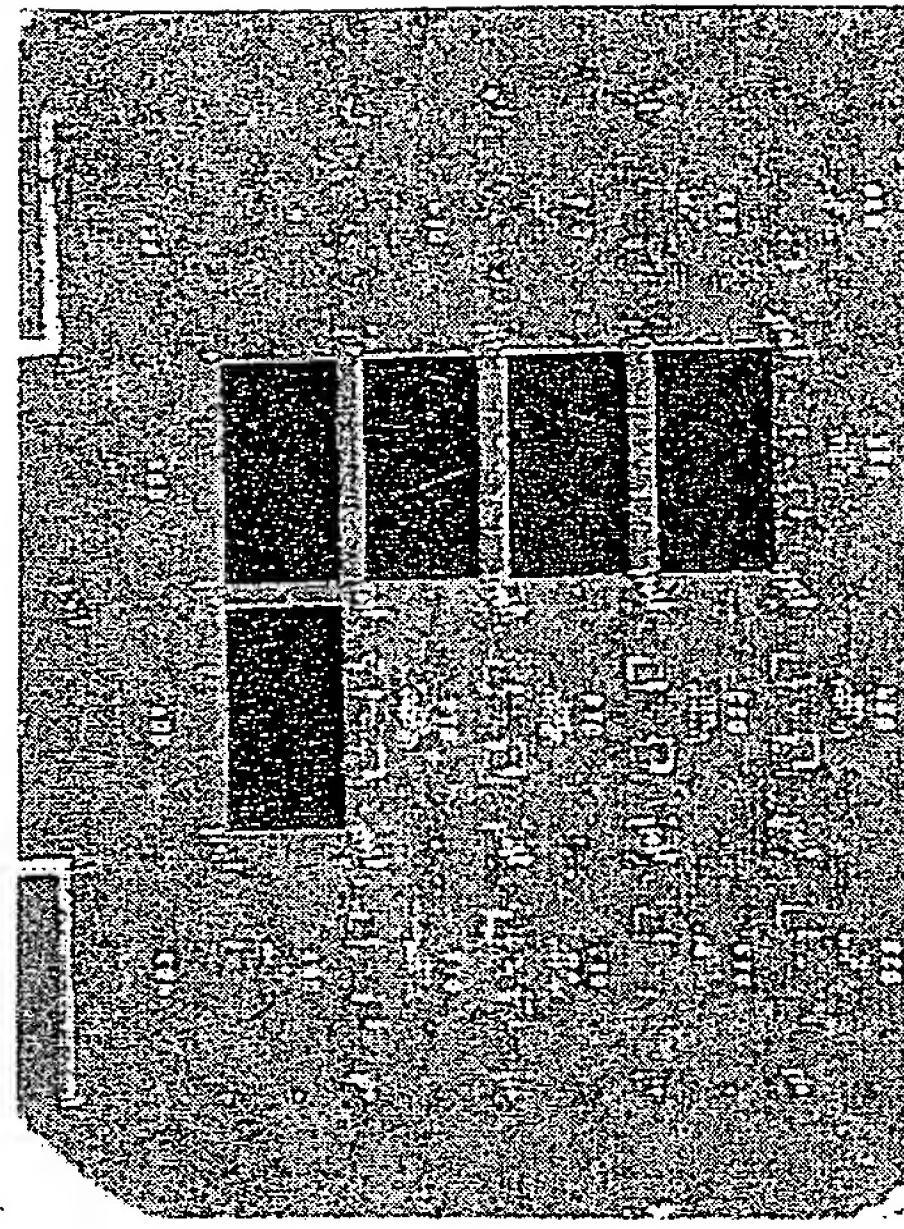
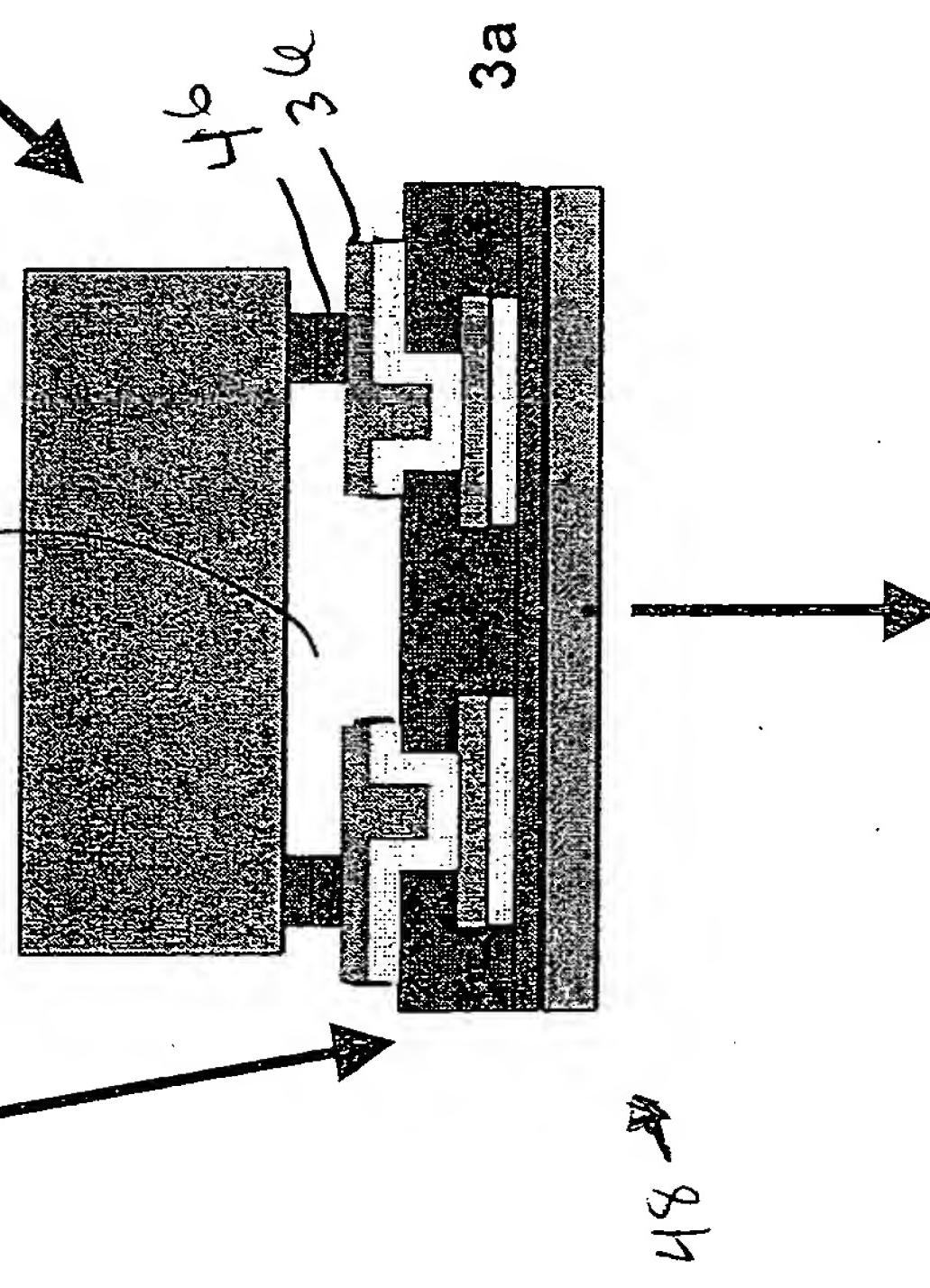
## Flip-Chip Bonding

K16, 3a

Retrieve substrate assembly and  
bumped die



3a) Flip chip bumped die to substrate

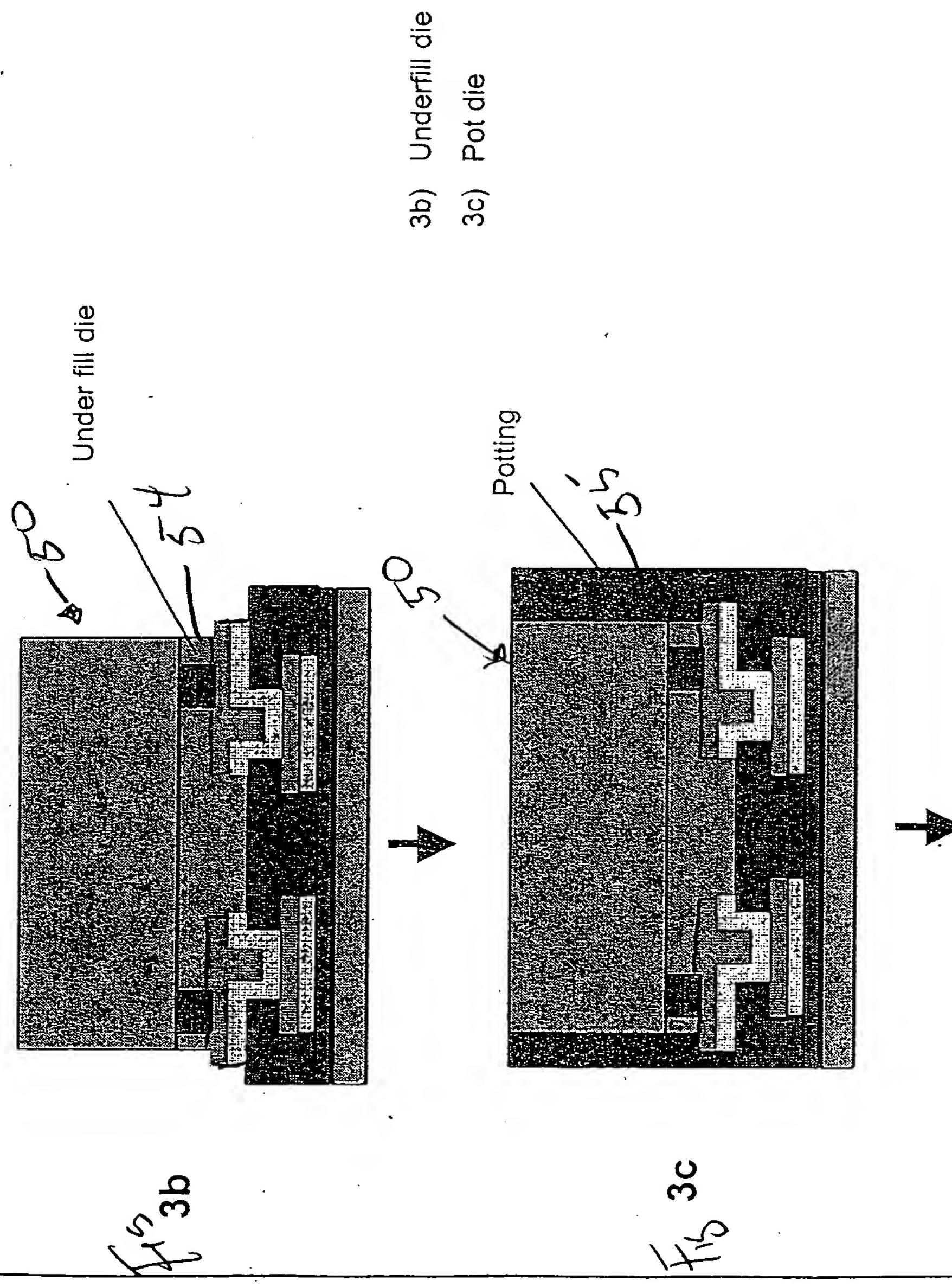


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## Reverse Neo Process

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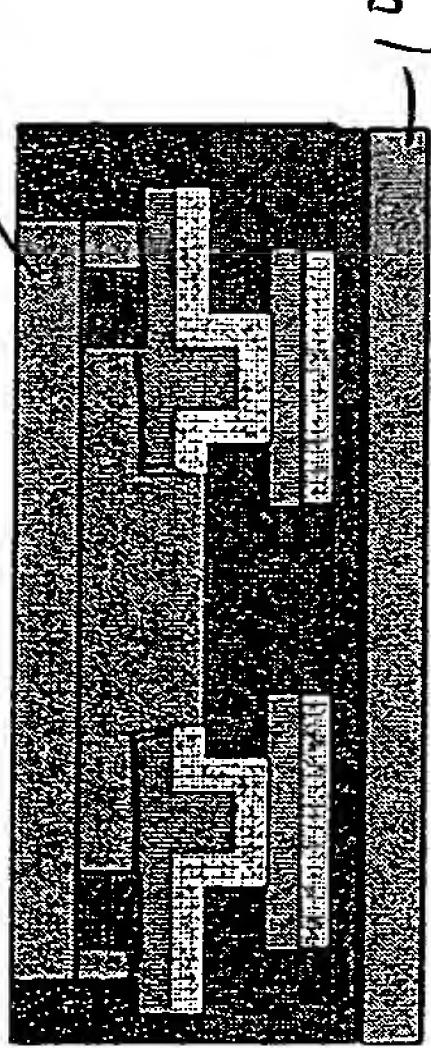
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# Reverse Neo Process

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Fig. 3d



- 3d) Thin wafer
- 3e) Release wafer from aluminum substrate
- 3f) Mask wafer for test pad etch

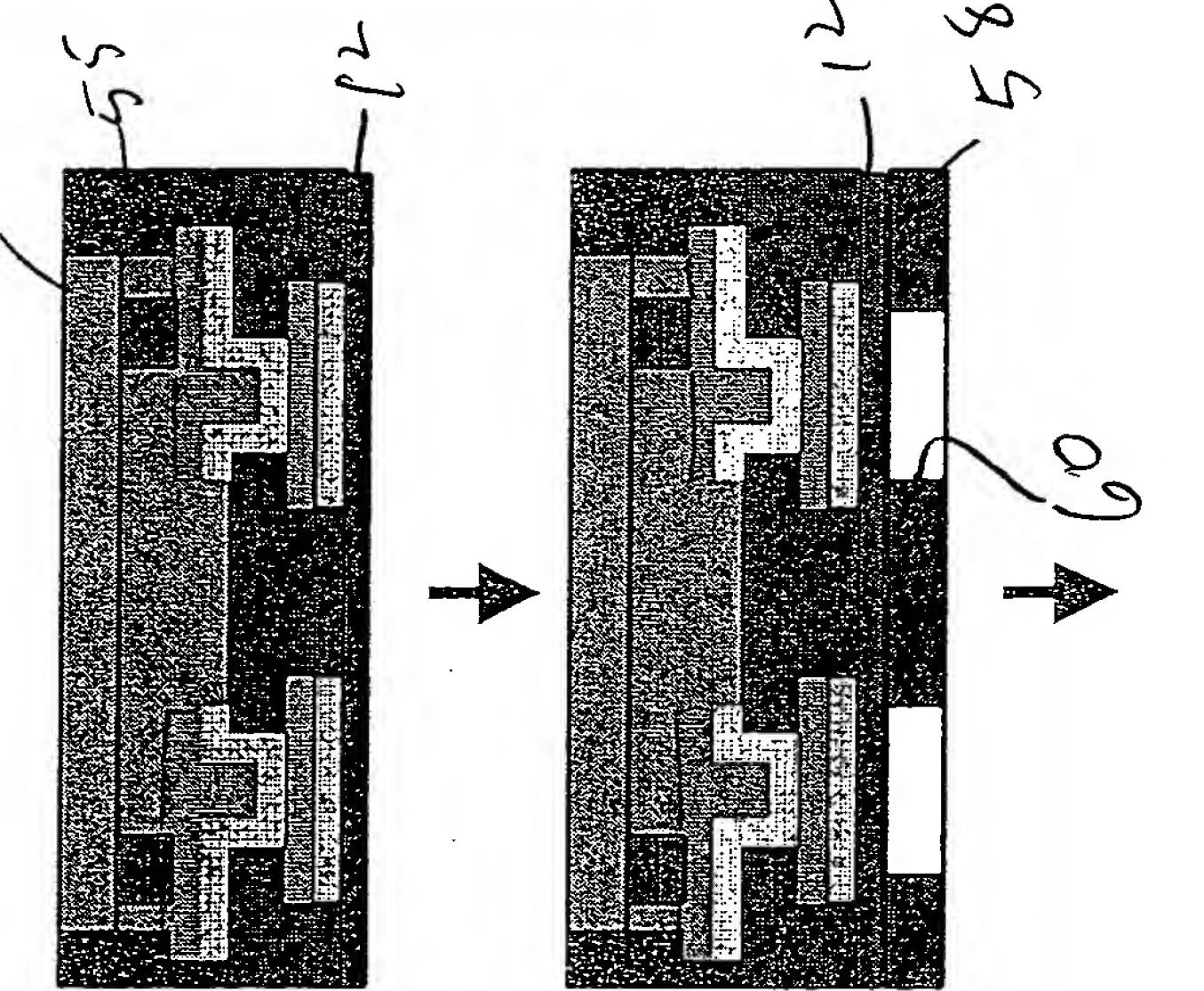
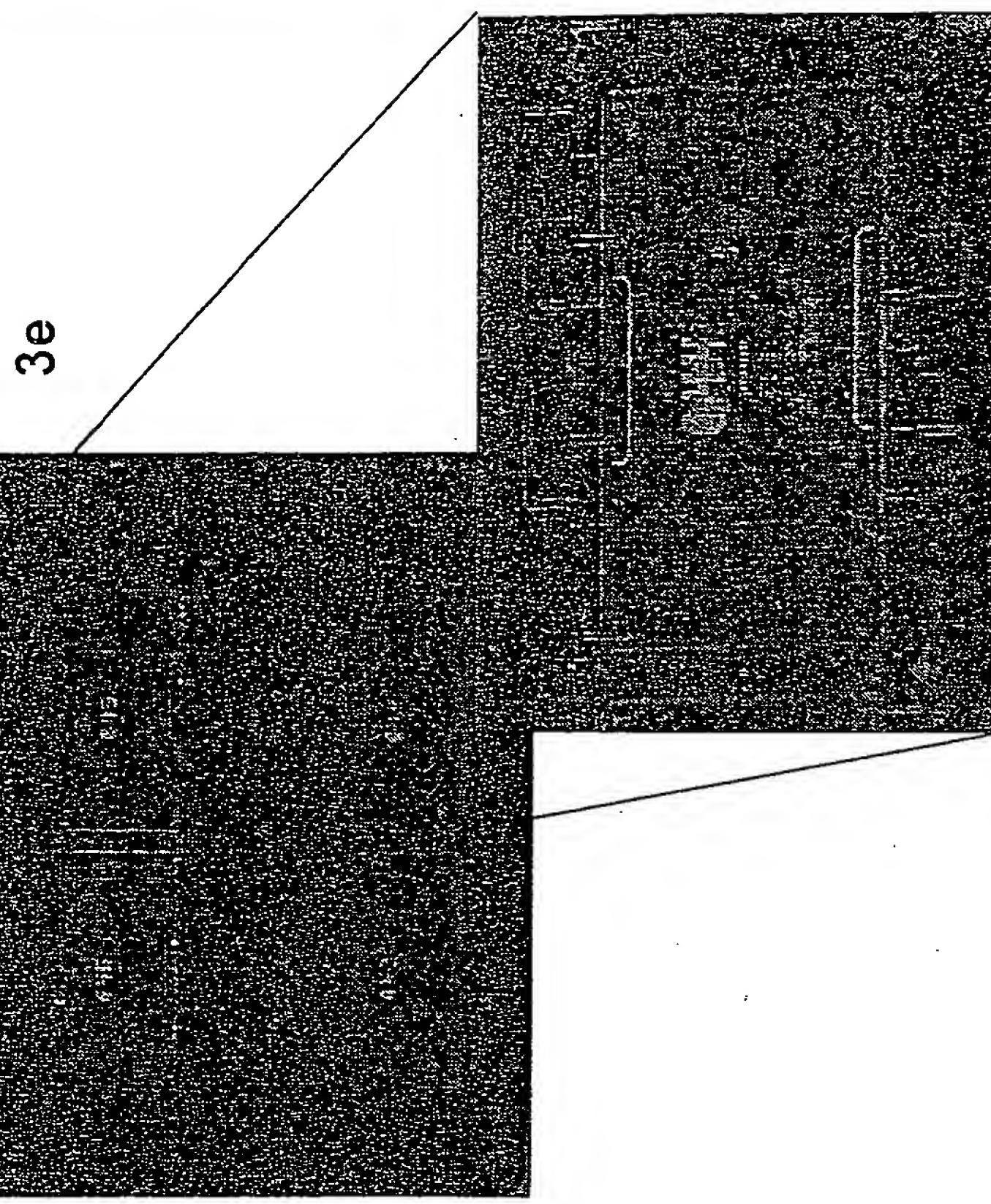


Fig. 3e

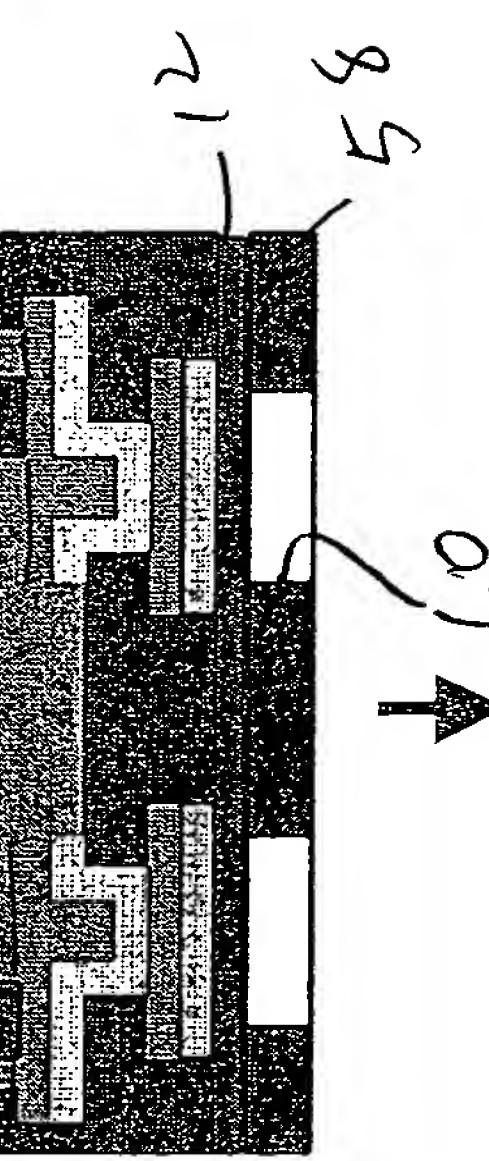


Fig. 3f

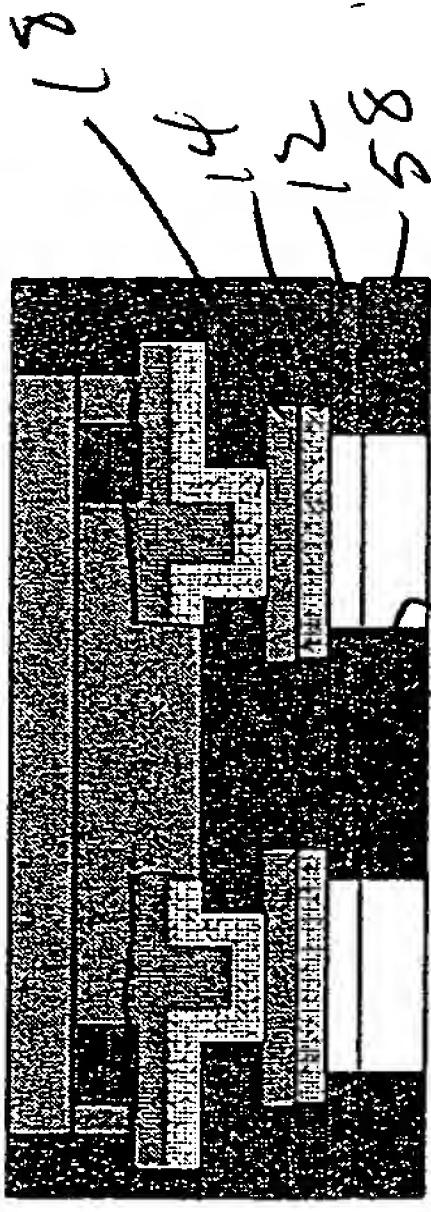
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# Reverse Neo Process

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Fig 3g



- 3g) Etch polyimide to expose test pads  
3h) Remove etch mask & test wafer  
3i) Dice wafer

Fig 3h

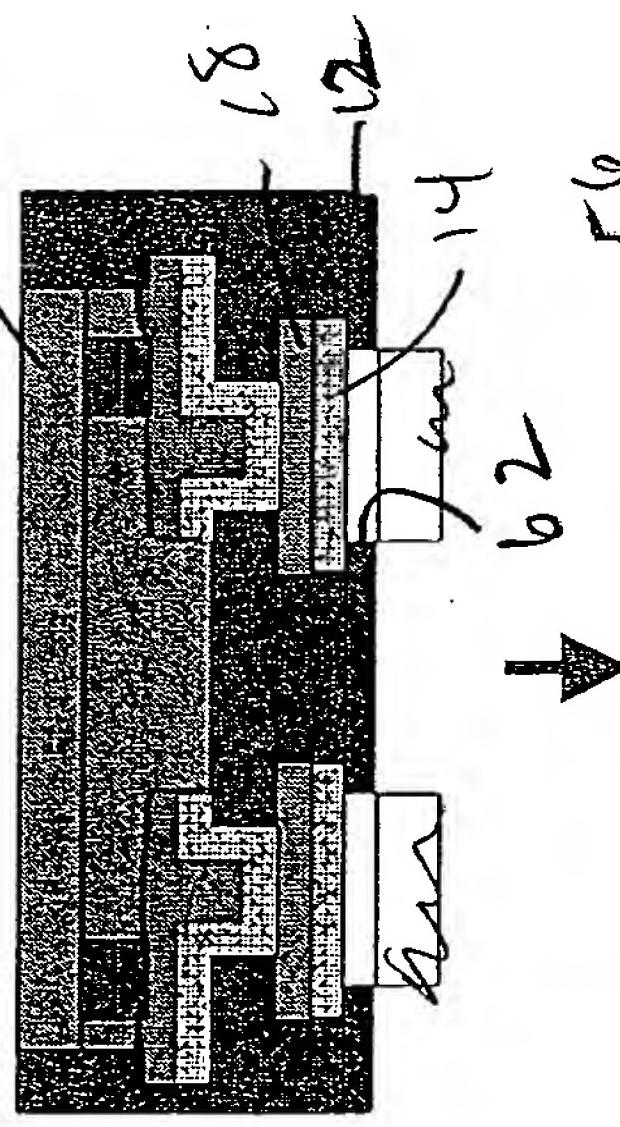
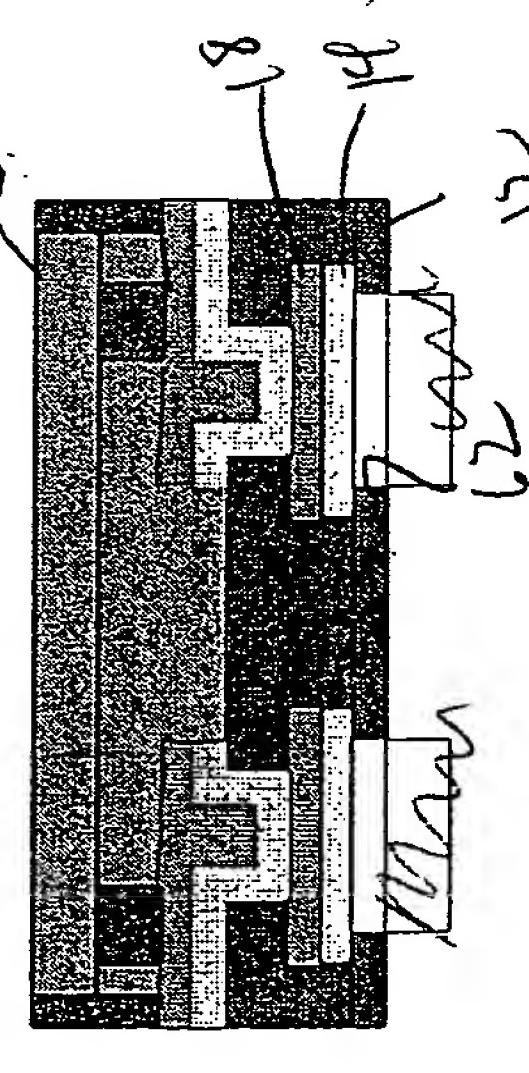


Fig 3i

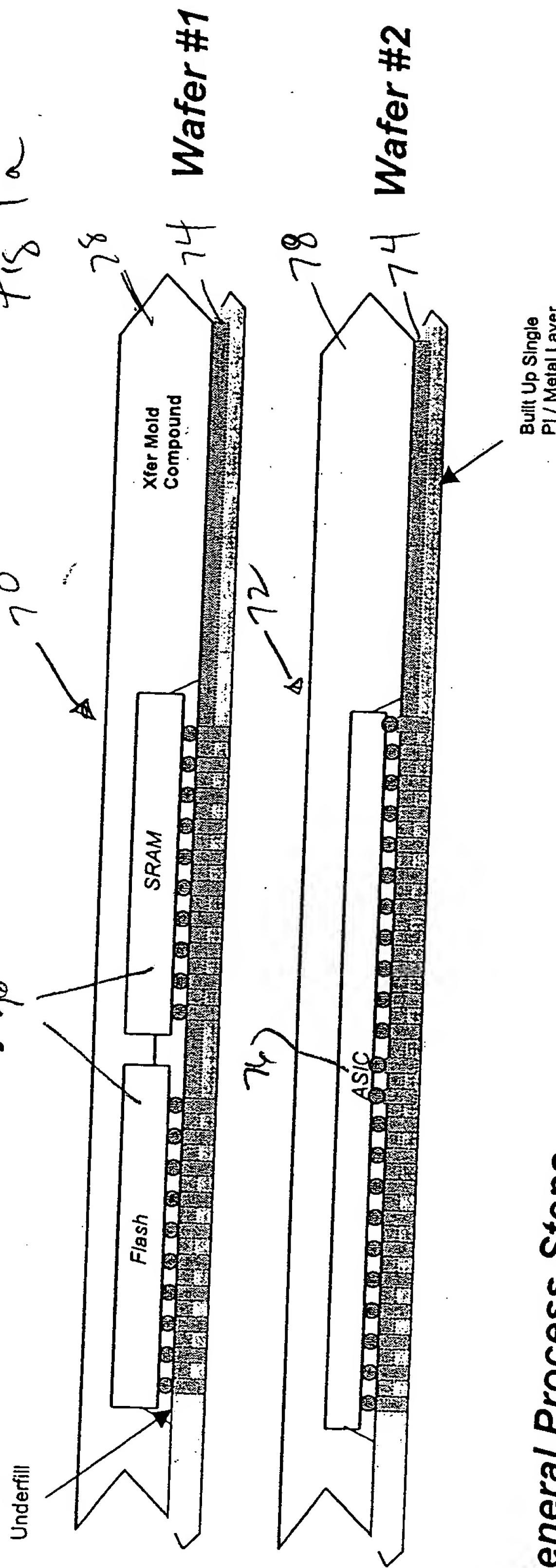


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# High Volume Reverse NEO Process

## #1) Wafer Built Up Assembly



## General Process Steps

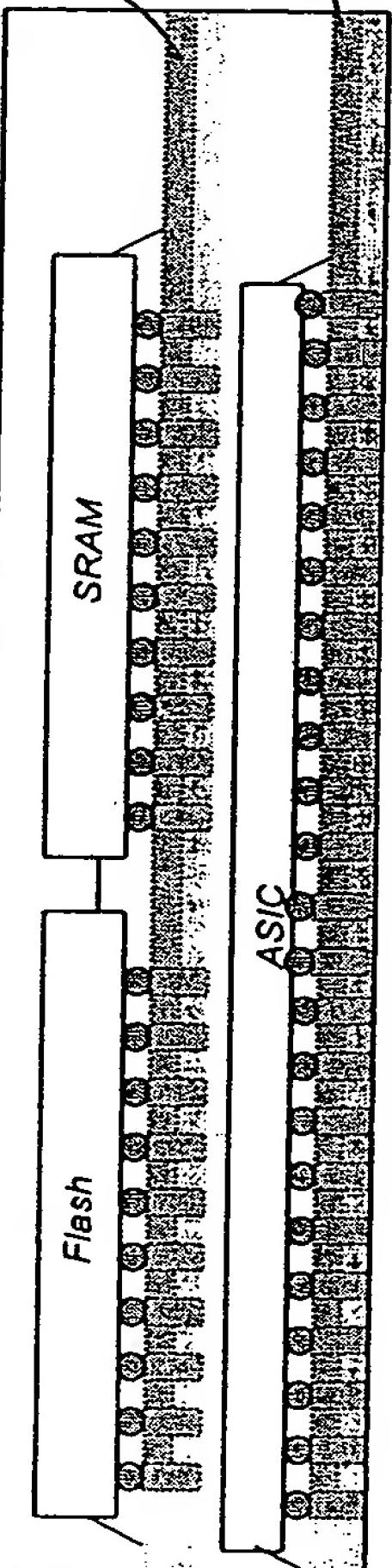
- 1) Screen Print Electrically Conductive Epoxy on Built-Up Laminate Substrates
- 2) Place Flip Chip Devices
- 3) Cure Epoxy
- 4) Underfill Devices
- 5) Xfer. Mold Devices

ISSUE - V1P1

# High Volume Reverse NEO Process

## 2) Stacked Wafer Strip Assembly

### General Process Steps

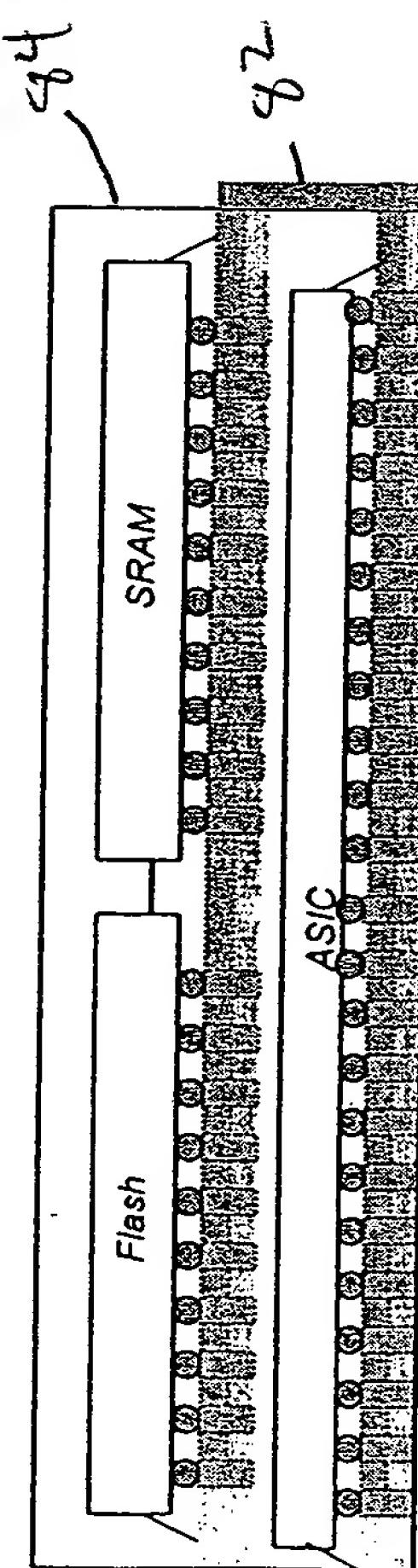


- 6) Release Carrier Film from Substrate  
(If Required)
- 7) Attach Memory and ASIC Wafers
- 8) Cut/Saw Wafers to Strips

Figs

## 3) Stacked Wafer Strip Assembly

### General Process Steps



- 9) Interconnect or Bus Wafers by  
Metallizing Wafer Stacks

150E - 150P

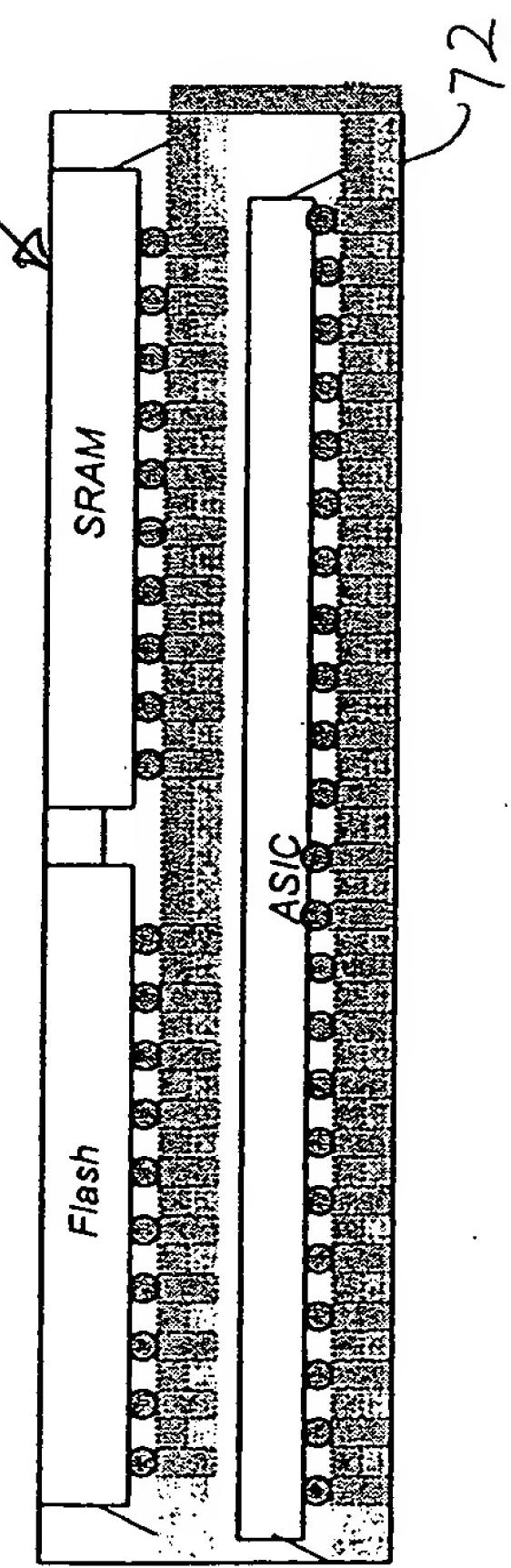
# High Volume Reverse NEO Process

## General Process Steps

### 4) Thinned and Sawed Assembly

Figs. 4 &  
80 →

### 10) Thin Stack Assembly

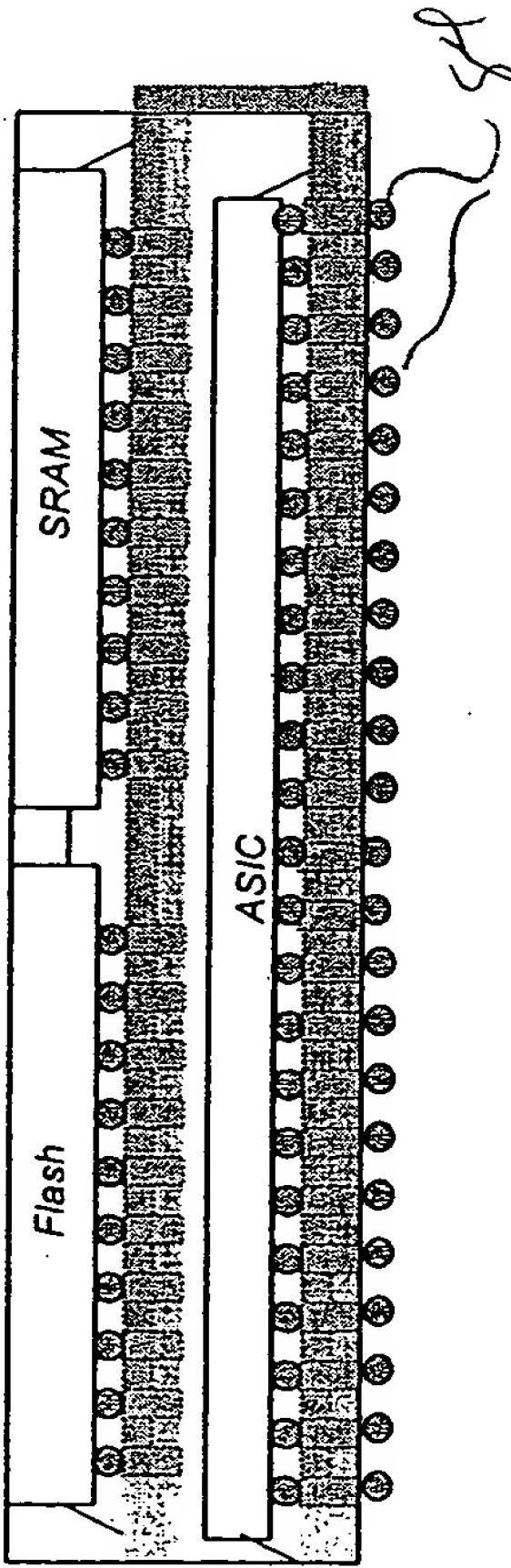


### 5) Thinned and Sawed Assembly

Figs. 4 &  
80 →

## General Process Steps

- 11) Solder Bump Stack
- 12) Singulate (Saw) into Individual Stacks



186 - VPP